


Search Notes 	Application/Control No. 10525737	Applicant(s)/Patent Under Reexamination SUEHIRO, NAOKI
	Examiner Flores, Leon	Art Unit 2611

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with SPE David Payne in regards to the patentability of the claims.	11/13/2007	LF
Searched in NPL (IEEE).	11/1/2007	LF
Checked for possible double patenting.	11/1/2007	LF
Consulted with SPE David Payne in regards to the new rejection.	8/27/2008	LF
Consulted with SPE David Payne in regards to the arguments.	2/13/2009	LF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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Examiner, Art Unit 2611